

### CMT826X High-Speed, Six-Channel Enhanced Digital Isolator

### 1 Features

- Safety-related certifications
  - DIN VDE V 0884-11: 2017-01
  - UL 1577 component recognition program
  - CSA certification according to IEC 60950-1, IEC 62368-1, IEC 61010-1 and IEC 60601-1 end equipment standards
  - CQC approval per GB4943.1-2022
  - TUV certification according to EN 60950-1, EN 62368-1 and EN 61010-1
- Robust electromagnetic compatibility
  - System-level ESD, EFT, and surge immunity
  - ±8 kV IEC 61000-4-2 contact discharge protection across isolation barrier
  - Low emissions
- Data rate: up to 150 Mbps
- Wide supply range: 2.5 to 5.5 V
- Operation temperature: -40°C to 125°C
- Robust isolation barrier
  - More than 40-year projected lifetime
  - Up to 5 kV<sub>RMS</sub> isolation rating
  - Up to 8 kV surge capability
  - ±250 kV/µs typical CMTI
- Default output high and low options
- Low power consumption, typical 1.5 mA per channel at 1 Mbps
- Low propagation delay: 9 ns typical (5V supplies)
- SOIC 16 package (wide body and narrow body)

## 2 Applications

- Industrial automatic control
- New energy vehicles
- Solar inverters
- Motor control
- Isolated SPI
- General purpose multichannel isolation

### 3 Description

The CMT826X series devices are high-performance, six channel digital isolators with as high as  $5.7~\mathrm{kV_{rms}}$  isolation voltage by means of silicon-dioxide (SiO2) insulation barrier.

The digital isolator is used for communication between two different power supply domains while prevents noise currents on a data bus or other circuits from entering the local ground and interfering with or damaging sensitive circuitry.

CMT826X device has six forward and up to three reversedirection channels. If the input power or signal is lost, the default output is high for the CMT826XH device and low for the CMT826XL device. See the Device Functional Modes section for further details.

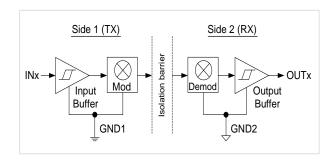
The isolator provides high electromagnetic immunity and low emissions at low-power consumption. Through innovative chip design and layout techniques, electromagnetic compatibility of the CMT826X device has been significantly enhanced to ease system-level ESD, EFT, surge, and emissions compliance.

The CMT826X series device is available in both narrow-body (NB) and wide-body (WB) 16-pin SOIC packages.

#### **Device Information**

Part No.	Package	Body Size (mm x mm)			
CMT826X	NB(N) SOIC-16	9.9 x 3.9			
CIVITOZOA	WB(W) SOIC-16	10.3 x 7.5			
Refer to section 14 for ordering information.					

#### Simplified Schematic



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# 4 Absolute Maximum Ratings

Table 1. Absolute Maximum Ratings[1]

Parameters	Symbol	Condition	Min.	Max.	Unit
Power supply voltage <sup>[2]</sup>	VDD1, VDD2		-0.5	6	V
Maximum input voltage	INx	x = A, B, C, D	-0.4	VDD+0.4	V
Maximum output voltage	OUTx	x = A, B, C, D	-0.4	VDD+0.4	V
Maximum Input / output pulse voltage	-	Pulse width should be less than 100 ns, and duty cycle should be less than 10%	-0.8	VDD+0.8	V
Common-mode transient immunity	CMTI			±250	kV/us
Output current	Io		-15	15	mA
Maximum surge immunity	-			8	kV
Operating temperature	T <sub>A</sub>		-40	125	°C
Storage temperature	T <sub>STG</sub>		-40	150	°C

#### Notes:

- [1]. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.
- [2]. All voltage values except differential I/O bus voltages are with respect to the local ground terminal (GND1 or GND2) and are peak voltage values.

# 5 Recommended Operating Conditions

**Table 2. Recommended Operating Conditions** 

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Power supply voltage	VDD1, VDD2		2.5	5	5.5	V
High level input voltage	V <sub>IH</sub>	VDDI: input side VDD	2		VDDI	V
Low level input voltage	V <sub>IL</sub>	VDDI: input side VDD	0		0.8	V
Data rate	DR		0		150	Mbps
Operating temperature	T <sub>A</sub>		-40	25	125	$^{\circ}$
Junction temperature	TJ		-40		150	$^{\circ}$

# 6 ESD Ratings

**Table 3. ESD Ratings** 

Parameter	Symbol	Condition	Max.	Unit
Electrostatic discharge V <sub>ESD</sub>	Human-body model (HBM)	±8000	\/	
	Charged-device model (CDM)	± 2000	V	

#### Notes:

- 1. IEC ESD strike is applied across the barrier with all pins on each side tied together creating a two-terminal device.
- 2. Testing is carried out in air or oil to determine the intrinsic contact discharge capability of the device.



**Caution!** ESD sensitive device. Precaution should be used when handling the device in order to prevent performance degradation or loss of functionality.

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## 7 Pin Description

Both narrow-body (N) and wide-body (W) 16-pin SOIC packages are available for the series part number CMT826A, CMT826B, CMT826C and CMT826D. The pin lists are shown as below.

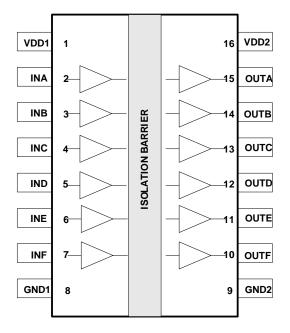


Figure 1. CMT826A Pin List

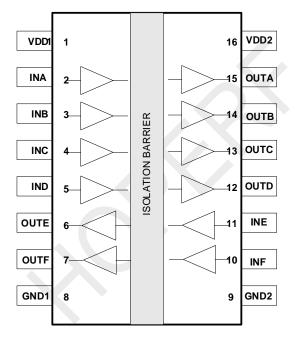


Figure 3. CMT826C Pin List

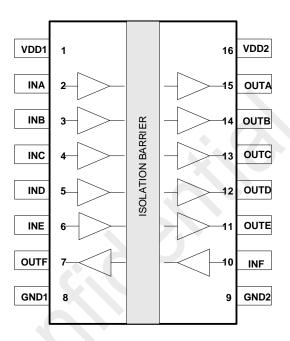


Figure 2. CMT826B Pin List

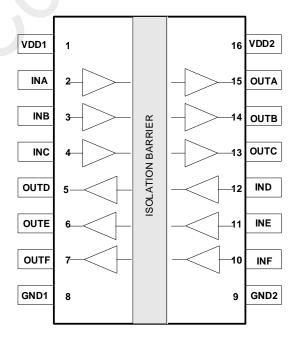


Figure 4. CMT826D Pin List

Din Name	Pin Number			Description	
Pin Name	CMT826A	CMT826B	CMT826C	CMT826D	Description
VDD1	1	1	1	1	Power supply for isolator side 1
INA	2	2	2	2	Input, channel A
INB	3	3	3	3	Input, channel B
INC	4	4	4	4	Input, channel C
IND	5	5	5	12	Input, channel D
INE	6	6	11	11	Input, channel E
INF	7	10	10	10	Input, channel F
GND1	8	8	8	8	Ground 1, the ground reference for isolator side 1
GND2	9	9	9	9	Ground 2, the ground reference for isolator side 2
OUTF	10	7	7	7	Output, channel F
OUTE	11	11	6	6	Output, channel E
OUTD	12	12	12	5	Output, channel D
OUTC	13	13	13	13	Output, channel C
OUTB	14	14	14	14	Output, channel B
OUTA	15	15	15	15	Output, channel A
VDD2	16	16	16	16	Power supply for isolator side 2

Table 4. CMT826A/6B/6C/6D Pin Description

# 8 Typical Application

## 8.1 Typical Application Schematic

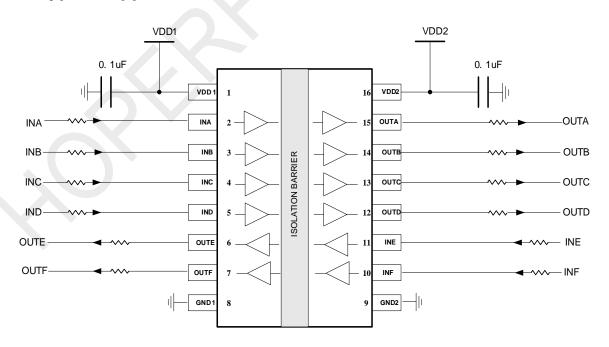


Figure 5. Typical Application Schematic (Take the CMT826C as an example)

Note: users should be careful not to connect ground and VDD reversely.

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### 8.2 PCB Layout Guidelines

The CMT826X requires a 0.1  $\mu$ F bypass capacitor in both input side and output side. The capacitor should be placed as close as possible to the package pin of VDD1 and VDD2 respectively. The figures below show the recommended PCB layout. Please make sure the space under the chip keeps free from planes, traces, pads and via. To enhance the robustness of design, users may also include resistors (50  $\sim$  300  $\Omega$ ) in series with the inputs and outputs if the system is excessively noisy. The series resistors also improve the system reliability such as latch-up immunity.

The typical output impedance of an isolator driver channel is approximately 50  $\Omega$  ± 40%. When driving loads where transmission line effects will be a factor, output pins should be appropriately terminated with controlled impedance PCB traces.

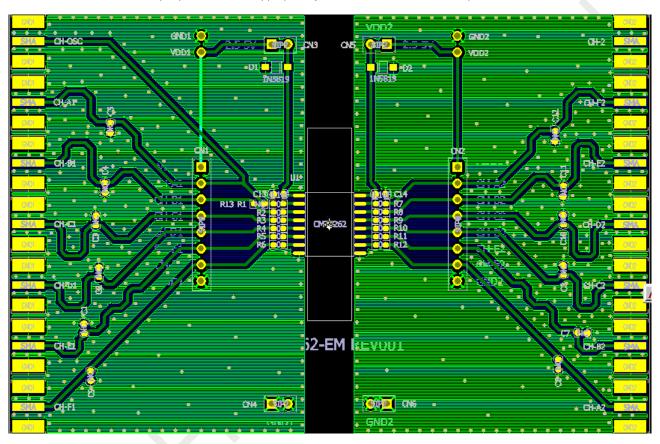


Figure 6. Recommended PCB Layout

# 9 Parameter Measurement Circuit Setup

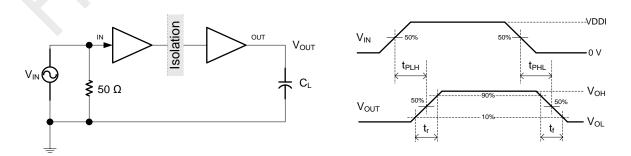


Figure 7. Switching Characteristics Test Circuit and Voltage Waveforms

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#### Notes:

- 1. The input pulse is supplied by a generator,  $V_{IN}$  has the following characteristics:  $f_{PULSE} \le 100$  kHz, 50% duty cycle,  $t_r \le 3$  ns,  $t_f \le 3$  n
- 2. Load capacitance influences the measurement results quite a lot, including instrumentation and fixture capacitance, totally no more than 15 pF loading is preferred.

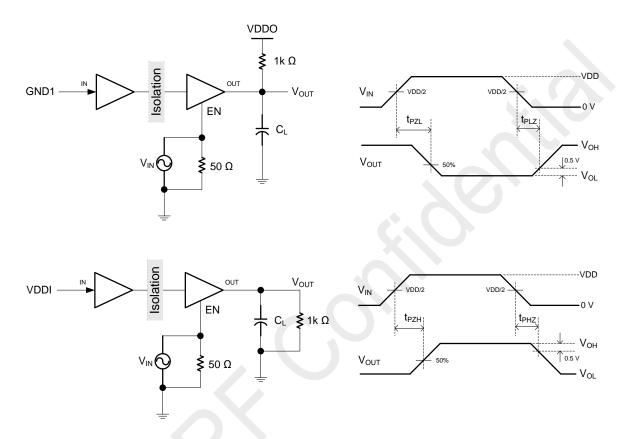


Figure 8. Enable/Disable Propagation Delay Time Test Circuit and Waveform

#### Notes:

- 1. The input pulse is supplied by a generator having the following characteristics:  $f_{PULSE} \le 10$  kHz, 50% duty cycle, tr  $\le 3$  ns, tf  $\le 3$  ns,  $Z_O = 50$   $\Omega$ .
- 2.  $C_L = 15 \text{ pF}$  and includes instrumentation and fixture capacitance within  $\pm 20\%$ .

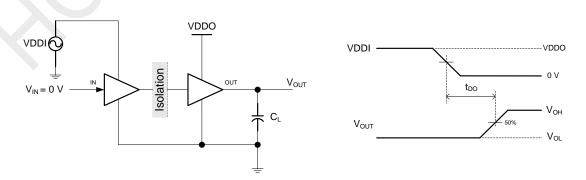


Figure 9. Default Output Delay Time Test Circuit and Voltage Waveforms

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#### Notes:

- 1.  $C_L = 15 \text{ pF}$  and includes instrumentation and fixture capacitance within  $\pm 20\%$ .
- 2. Power supply ramp rate = 10 mV/ns.

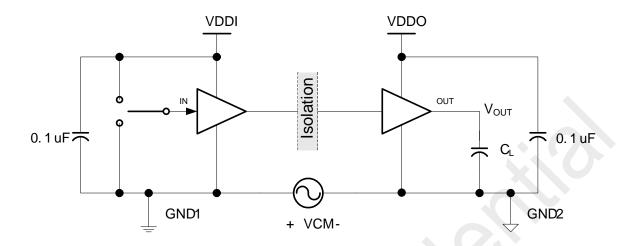


Figure 10. Common-Mode Transient Immunity Test Circuit

#### Notes:

1.  $C_L = 15 \text{ pF}$  and includes instrumentation and fixture capacitance within  $\pm 20\%$ .

# 10 Electrical Specifications

### 10.1 Electrical Characteristics

VDD1 =2.5V~5.5V, VDD2= 3.0V~5.5V, TA= -40 to 125  $^{\circ}$ C. Unless otherwise noted, typical values are at VDD1=5V, VDD2=5V, TA=25  $^{\circ}$ C.

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Power on reset	$V_{POR}$	POR threshold as during power- up		2.3		V
	V <sub>HYS</sub>	POR threshold hysteresis		0.1		V
	V <sub>IT</sub>	Input threshold at rising edge		1.6		V
Input threshold	V <sub>ITHYS</sub>	Input threshold hysteresis		0.4		V
High level input voltage	V <sub>IH</sub>		2			V
Low level input voltage	V <sub>IL</sub>				0.8	V
High level output voltage	V <sub>OH</sub>	I <sub>OH</sub> =-4mA	VDD- 0.3			V
Low level output voltage	V <sub>OL</sub>	I <sub>OL</sub> = 4mA			0.3	V
Output impedance	R <sub>o</sub>			50		Ω
Input pull high or low current	Ipull			13		uA
Start-up time after POR	trbs			30		us
Common mode transient	CMTI		150	250	270	kV/us

**Table 5. Electrical Characteristics** 

## 10.2 Supply Current Characteristics with 5 V Supply

VDD1 = VDD2 = 5V,  $T_A$ = -40 to 125 °C.

Table 6. Supply Current Characteristics with 5 V Supply

Parameter	Symbol	Тур.	Max.	Unit
CMT826A				
Supply current	I <sub>DD1</sub>	1.34		mA
EN = VDDI,V <sub>IN</sub> =0 V	I <sub>DD2</sub>	3.09		mA
Supply current: device is disabled.	I <sub>DD1</sub>	10.56	<b>&gt;</b> ()	mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	3.24		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.88		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	3.28		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.94		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	4.47		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	8.22		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	28.96		mA
CMT826B			·	
Supply current	I <sub>DD1</sub>	1.69		mA
$EN = VDDI$ , $V_{IN} = 0$ V	I <sub>DD2</sub>	3.36		mA
Supply current: device is disabled.	I <sub>DD1</sub>	9.25		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	4.98		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.50		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	4.39		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.84		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	6.42		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	9.68		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	27.68		mA
CMT826C	- II		1	
Supply current	I <sub>DD1</sub>	2.13		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	2.99		mA
Supply current: device is disabled.	I <sub>DD1</sub>	8.27		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	6.12		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.26		mA
All channels switching with 1 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	4.74		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.97		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	6.32		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	13.87		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	22.16		mA
MT826D	1		1	1
Supply current	I <sub>DD1</sub>	2.56		mA

Parameter	Symbol	Тур.	Max.	Unit
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	2.51		mA
Supply current: device is disabled.	I <sub>DD1</sub>	7.31		mA
EN = VDDI, VIN =VDDI,	I <sub>DD2</sub>	7.13		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.04		mA
All channels switching with 1 Mbps square wave input, CL = 15 pF	I <sub>DD2</sub>	4.99		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	6.20		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	6.29		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	18.30		mA
All channels switching with 100 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	19.04		mA

Table 7. Supply Current with 5 V Supply- Characteristics of CMT826X

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit	
Data rate	DR		0	150		Mbps	
Minimum pulse width	PW	See figure 6, CL = 15 pF		5	~	ns	
Propagation delay rising	t <sub>PLH</sub>	See figure 6, C <sub>L</sub> = 15 pF	<b>\$</b> . (	7.53		ns	
Propagation delay falling	t <sub>PHL</sub>	See figure 6, CL = 15 pF		8.43		ns	
Pulse width distortion	PWD	See figure 6, CL = 15 pF		0.9		ns	
Rising time	tr	See figure 6, C <sub>L</sub> = 15 pF		0.8		ns	
Falling time	tf	See figure 6, CL = 15 pF		0.85		ns	
Peak eye diagram Jitter	t <sub>JIT</sub> (PK)			400		ps	
Channel-to-channel delay Skew	t <sub>SK</sub> (c2c)	4		0.3	2.5	ns	
Part-to-part delay skew	t <sub>SK</sub> (p2p)				5	ns	

# 10.3 Supply Current Characteristics with 3.3 V Supply

VDD1 = VDD2 = 3.3V,  $T_A$ = -40 to 125 °C.

Table 8. Supply Current Characteristics with 3.3 V Supply

Parameter	Symbol	Тур.	Max.	Unit
CMT826A				
Supply current	I <sub>DD1</sub>	1.34		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	3.08		mA
Supply current: device is disabled.	I <sub>DD1</sub>	10.46		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	3.23		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.89		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	3.33		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.95		mA

Parameter	Symbol	Тур.	Max.	Unit
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	4.88		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	7.10		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	21.12		mA
CMT826B	1			
Supply current	I <sub>DD1</sub>	1.73		mA
EN = VDDI, V <sub>IN</sub> =0 V	I <sub>DD2</sub>	3.28		mA
Supply current: device is disabled.	I <sub>DD1</sub>	9.43		mA
EN = VDDI,V <sub>IN</sub> =VDDI,	I <sub>DD2</sub>	4.89		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.59	<b>\</b>	mA
All channels switching with 1 Mbps square wave input 76 signal.	I <sub>DD2</sub>	4.23		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.78		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	5.58		mA
Construction of ACO Miles and a service stand in section AC signal	I <sub>DD1</sub>	9.61		mA
Supply current: 100 Mbps square wave clock input AC signal. All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	19.86		mA
CMT826C	-002	13.00		
	I <sub>DD1</sub>	2.11		mA
Supply current $EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	2.97		mA
Cupply gurrents device in displied	I <sub>DD1</sub>	8.22		mA
Supply current: device is disabled.  EN = VDDI, V <sub>IN</sub> =VDDI,	I <sub>DD2</sub>	6.09		mA
	I <sub>DD1</sub>	5.20		mA
Supply current: 1 Mbps square wave clock input AC signal.  All channels switching with 1 Mbps square wave input, C <sub>L</sub> = 15 pF		4.66		
	I <sub>DD2</sub>	5.63		mA m^
Supply current: 10 Mbps square wave clock input AC signal. All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD1</sub>			mA 
	I <sub>DD2</sub>	5.71		mA
Supply current: 100 Mbps square wave clock input AC signal.  All channels switching with 100 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD1</sub>	11.92		mA_
	I <sub>DD2</sub>	16.61		mA
CMT826D Supply current	IDD1	2.54	<u> </u>	mΛ
EN = VDDI, $V_{IN}$ =0 V	IDD1	2.50		mA mA
Supply current: device is disabled.	IDD1	7.27		mA
EN = VDDI, VIN =VDDI,	IDD2	7.10		mA
Supply current: 1 Mbps square wave clock input AC signal.	IDD1	4.97		mA
All channels switching with 1 Mbps square wave input $N_c$ signal.	IDD2	4.91		mA
Supply current: 10 Mbps square wave clock input AC signal.	IDD1	5.70		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	IDD2	5.78		mA
Supply current: 100 Mbps square wave clock input AC signal.	IDD1	14.70		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	IDD2	14.74		mA

Table 9. Supply Current with 3.3 V Supply - Characteristics of CMT826X

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Data rate	DR		0	150		Mbps
Minimum pulse width	PW	See figure 6, CL = 15 pF		5		ns
Propagation delay rising	t <sub>PLH</sub>	See figure 6, CL = 15 pF		8		ns
Propagation delay falling	t <sub>PHL</sub>	See figure 6, CL = 15 pF		8.7		ns
Pulse width distortion	PWD	See figure 6, CL = 15 pF		0.7		ns
Rising time	tr	See figure 6, CL = 15 pF		1		ns
Falling time	tf	See figure 6, CL = 15 pF		0.9	<b>&gt;</b> . (7)	ns
Peak eye diagram Jitter	t <sub>JIT</sub> (PK)			400		ps
Channel-to-channel Delay Skew	t <sub>SK</sub> (c2c)			0.5	2.5	ns
Part-to-part delay skew	t <sub>SK</sub> (p2p)				5	ns

## 10.4 Supply Current Characteristics with 2.5 V Supply

VDD1 = VDD2 = 2.5 V,  $T_A$ = -40 to 125 °C.

Table 10. Supply Current Characteristics with 2.5 V Supply

Parameter	Symbol	Тур.	Max.	Unit
CMT826A				
Supply current	I <sub>DD1</sub>	1.33		mA
EN = VDDI, V <sub>IN</sub> =0 V	I <sub>DD2</sub>	3.16		mA
Supply current: device is disabled.	I <sub>DD1</sub>	10.46		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	3.30		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.87		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	3.37		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	6.00		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	5.80		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.44		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	16.83		mA
CMT826B				
Supply current	I <sub>DD1</sub>	1.67		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	3.34		mA
Supply current: device is disabled.	I <sub>DD1</sub>	9.16		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	4.95		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.42		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	4.26		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.55		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	5.29		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	7.30		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	16.00		mA
CMT826C	•			
Supply current	I <sub>DD1</sub>	2.16		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	2.95		mA
Supply current: device is disabled.	I <sub>DD1</sub>	8.33		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	6.04		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.26		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	4.59		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	5.56		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	5.40		mA
Supply current: 100 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	9.37		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	13.51		mA
CMT826D	•			
Supply current	IDD1	2.54		mA

Parameter	Symbol	Тур.	Max.	Unit
$EN = VDDI, V_{IN} = 0 V$	IDD2	2.49		mA
Supply current: device is disabled.	IDD1	7.24		mA
EN = VDDI, VIN =VDDI,	IDD2	7.08		mA
0 1	IDD1	4.94		mA
Supply current: 1 Mbps square wave clock input AC signal. All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	IDD2	4.88		mA
Supply current: 10 Mbps square wave clock input AC signal.	IDD1	5.47		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	IDD2	5.53		mA
Supply current: 100 Mbps square wave clock input AC signal.	IDD1	11.47		mA
All channels switching with 100 Mbps square wave input, $C_L = 15 \text{ pF}$	IDD2	11.91		mA

Table 11. Supply Current with 2.5 V Supply - Characteristics of CMT826X

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Data rate	DR		0	150		Mbps
Minimum pulse width	PW	See figure 6, CL = 15 pF		5		ns
Propagation delay rising	t <sub>PLH</sub>	See figure 6, C <sub>L</sub> = 15 pF	A . (	8.63		ns
Propagation delay falling	t <sub>PHL</sub>	See figure 6, CL = 15 pF		9.11		ns
Pulse width distortion	PWD	See figure 6, CL = 15 pF		0.48		ns
Rising time	tr	See figure 6, C <sub>L</sub> = 15 pF		1.04		ns
Falling time	tf	See figure 6, CL = 15 pF		1.23		ns
Peak eye diagram Jitter	t <sub>JIT</sub> (PK)			400		ps
Channel-to-channel Delay Skew	t <sub>SK</sub> (c2c)			0.7		ns
Part-to-part delay skew	t <sub>SK</sub> (p2p)			0		ns

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### 10.5 Typical Characteristics

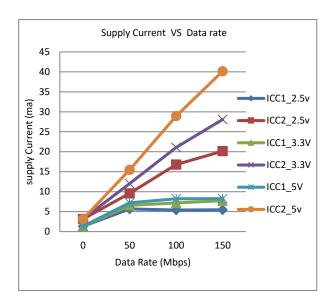


Figure 11-1. Supply Current vs. Data Rate (with 15-pF Load) T<sub>A</sub>=25 <sup>°</sup>C C<sub>L</sub>=15pF

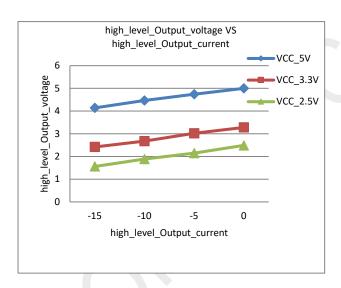


Figure 11-3. High-Level Output Voltage vs. High-Level Output Current ( $T_A$ =25 $^{\circ}$ C)

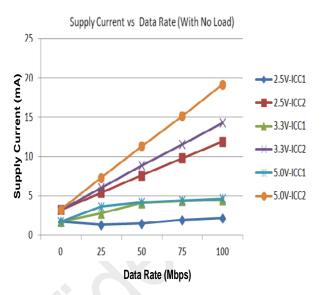


Figure 11-2. Supply Current vs. Data Rate (with No Load) T<sub>A</sub>=25 °C C<sub>L</sub>=No Load

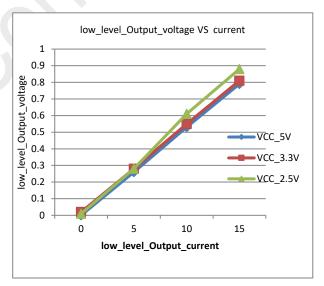


Figure 11-4. Low-Level Output Voltage vs. Low-Level Output Current  $(T_A=25^{\circ}C)$ 

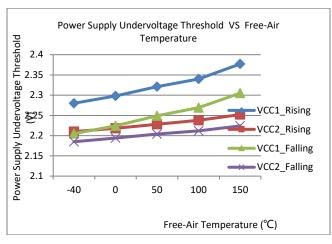


Figure 11-5. Power Supply Under-voltage Threshold vs. Free-Air Temperature

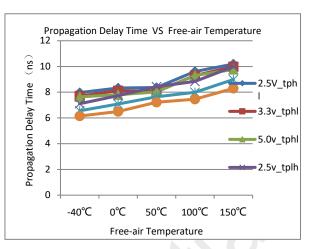


Figure 11-6. Propagation Delay Time
vs. Free-Air Temperature

## 10.6 Insulation Specifications

**Table 12. Insulation Specifications** 

Parameters	Sym.	Constition	Va	Value		
r ai ailletei S		Condition	NB SOIC-16	WB SOIC-16	Unit	
External clearance[1]	CLR	The shortest terminal-to-terminal distance through air	4.0	8.0	mm	
External creepage <sup>[1]</sup>	CRP	The shortest terminal-to-terminal distance across the package surface	4.0	8.0	mm	
Distance through insulation	DTI	Minimum internal gap	32	32	um	
Comparative tracking index	СТІ	DIN EN 60112 (VDE 0303-11); IEC 60112	> 400	> 600	V	
Material group			1	1	-	
		Rated mains voltage ≤ 300 V <sub>RMS</sub>	I	I	-	
Overvoltage category per IEC 60664-1	-	Rated mains voltage ≤ 600 V <sub>RMS</sub>	I-IV	I-IV	-	
000011		Rated mains voltage ≤ 1000 V <sub>RMS</sub>	1-111	1-111	-	
DIN VDE V 0884-11:2017-01 <sup>[2]</sup>						
Maximum peak isolation voltage	V <sub>IORM</sub>		565	2121	$V_{pk}$	
Maximum isolation working voltage	V <sub>IOWM</sub>	AC voltage (sine wave); Time dependent dielectric breakdown (TDDB) test	400	1500	V <sub>RMS</sub>	
J. T. J.	VIOVVIVI	DC voltage		2121	$V_{DC}$	
Maximum transient isolation voltage	V <sub>IOTM</sub>	V <sub>TEST</sub> = V <sub>IOTM</sub> ,t = 60 s (qualification); t = 1 s (100% production)	5300	8000	$V_{pk}$	
Maximum surge isolation voltage <sup>[3]</sup>	V <sub>IOSM</sub>	Test method per IEC60065, 1.2/50 us waveform, V <sub>TEST</sub> = 1.6 x V <sub>IOSM</sub> (qualification)	5300	8000	$V_{pk}$	
Apparent charge <sup>[4]</sup>	α .	Method a: After I/O safety test subgroup 2/3, $V_{\text{ini}} = V_{\text{IOTM}},  t_{\text{ini}} = 60 \text{ s};$ $V_{\text{pd(m)}} = 1.2 \times V_{\text{IORM}},  t_{\text{m}} = 10 \text{ s}$		<5	≤5pC	
Apparent charge.	q <sub>pd</sub>	Method a: After environmental tests subgroup 1, $V_{ini} = V_{IOTM}$ , $t_{ini} = 60 \text{ s}$ ; $V_{pd(m)} = 1.6 \times V_{IORM}$ , $t_m = 10 \text{ s}$		<5	⊒υμΟ	

		Method b1: At routine test (100% production) and preconditioning (type test) $V_{\text{ini}} = V_{\text{IOTM}}, \ t_{\text{ini}} = 1 \ \text{s};$ $V_{\text{pd(m)}} = 1.875 \ \text{x} \ V_{\text{IORM}}, \ t_{\text{m}} = 1 \ \text{s}$		<5		
Isolation capacitance, input to output <sup>[5]</sup>	C <sub>IO</sub>	V <sub>IO</sub> = 0.4 x sin (2πft), f = 1 MHz	1.2	1.2	pF	
Isolation resistance, input to output <sup>[5]</sup>	R <sub>IO</sub>	V <sub>IO</sub> = 500 V	>1010	>1010	Ω	
UL 1577						
Withstand isolation voltage	V <sub>ISO</sub>	$V_{TEST} = V_{ISO}$ , $t = 60$ s (qualification); $V_{TEST} = 1.2 \times V_{ISO}$ , $t = 1$ s (100% production)	3750	5700	$V_{RMS}$	

#### Notes:

- [1]. Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance. Creepage and clearance on a printed-circuit board are equal in certain cases. Techniques such as inserting grooves and ribs on printed-circuit board can help to improve the specifications.
- [2]. This coupler is suitable for safe electrical insulation only within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.
- [3]. Testing is carried out in air or oil to determine the intrinsic surge immunity of the isolation barrier.
- [4]. Apparent charge is electrical discharge caused by a partial discharge (pd).
- [5]. All pins on each side of the barrier are tied together creating a two-terminal device.

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### 10.7 Safety-related Certifications

**Table 13. Safety-related Certifications** 

VDE	UL		CQC	TUV
DIN VDE V0884- 11:2017-01	UL 1577 Component Recognition Program	Approved under CSA Component Acceptance Notice 5A	GB 4943.1-2011	EN 61010-1:2010 (3rd Ed) and EN 60950- 1:2006/A2: 2013
Certificate number: pending	Certificate number: UL-US-2439077-1	Certificate number: UL-CA-2429797-0	Certificate number: CQC11-471543- 2022	Client ID number: pending

### 10.8 Safety Limiting Values

Safety limiting intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the I/O can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures

**Table 14. Safety Limiting Values** 

Parameters	Cumbal	Test Condition	Va	Unit	
rarameters	Symbol	rest Condition	NB SOIC-16	WB SOIC-16	Unit
		$R_{\theta JA} = 140 \text{ °C/W}, V_I = 5.5 \text{ V},$ $T_J = 125 \text{ °C}, T_A = 25 \text{ °C}$	160		mA
Safety input, output, or supply current	Is	$R_{\theta JA} = 84  ^{\circ} C/W,  V_I = 5.5  V, \ T_J = 125  ^{\circ} C,  T_A = 25  ^{\circ} C$		237	mA
Total power dissipation at 25°C	Ps			1499	mW
Case temperature	Ts		125	125	$^{\circ}$

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## 10.9 Thermal Information

**Table 15. Thermal Information** 

Parameter	Symbol	Valu	Unit	
Faranietei	Symbol	NB SOIC-16	WB SOIC-16	Onit
Junction-to-ambient thermal resistance	$\theta_{JA}$	78.9	78.9	°C/W
Junction-to-case (top) thermal resistance	θ <sub>JC</sub> (top)	41.1	41.6	°C/W
Junction-to-board thermal resistance	$\theta_{JB}$	49.5	43.6	°C/W

## 11 Function Description

### 11.1 Function Overview

The CMT826X device is a high-performance, quad-channel digital isolator with 5700  $V_{RMS}$  isolation ratings. CMT826X has an On-Off keying (OOK) modulation scheme to transmit the digital data across a silicon dioxide based isolation barrier. The transmitter sends a high-frequency carrier across the barrier to represent one digital state and sends no signal to represent the other digital state. The receiver demodulates the signal after advanced signal conditioning and produces the output through a buffer stage. If the ENx pin is low then the output goes to high impedance. The CMT826X also incorporates advanced circuit techniques to maximize the CMTI performance and minimize the radiated emissions due to the high frequency carrier and IO buffer switching. The figure below shows a conceptual detail of how the On-Off keying scheme works.

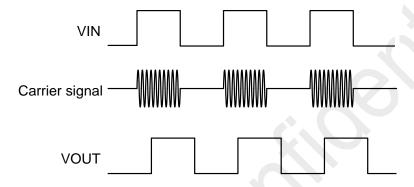


Figure 12. On-Off Keying Based Modulation Scheme

### 11.2 Functional Modes

The table below lists the functional modes of CMT826X.

Table 16. Function Table<sup>[1]</sup>

V <sub>DD1</sub>	V <sub>DD2</sub>	Input (INx) <sup>[2]</sup>	Output Enable (ENx)	Output (OUTx)	Comment
		Н	H or open	Н	Normal operation: The channel output assumes the logic state of
D	511	L	H or open	L	its input
PU	PU	Open	H or open	Default	Default mode: when INx is open, the corresponding channel output goes to its default logic state
Х	PU	X	L	Z	A low value of output enabling will output the high impedance
PD	PU	х	H or open	Default	Default mode: when VDDI is unpowered, a channel output assumes the logic state based on the selected default option.  When VDD1 transitions from unpowered to powered-up, a channel output assumes the logic state of the input.  When VDD1 transitions from powered-up to unpowered, channel output assumes the selected default state
Х	PD	Х	Х	Undetermined	When VDD2 is unpowered, a channel output is undetermined <sup>[3]</sup> . When VDD2 transitions from unpowered to powered-up, a channel output assumes the logic state of the input

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#### Notes:

- [1]. VDDI = Input-side VDD; VDD2 = output-side VDD; PU = Powered up (VDD ≥ 2.6 V); PD = Powered down (VDD ≤ 1.7 V); X = Irrelevant; H= High level; L = Low level; Z = High Impedance.
- [2]. A strongly driven input signal can weakly power the floating VDD through an internal protection diode and cause undetermined output.
- [3]. The outputs are in undetermined state when 1.7 V < VDD1, VDD2< 2.5V.

### 11.3 Insulation Lifetime

Insulation lifetime projection data is collected by using industry-standard Time Dependent Dielectric Breakdown (TDDB) test method. In this test, all pins on each side of the barrier are tied together creating a two-terminal device and high voltage applied between the two sides; See the figure below for TDDB test setup. The insulation breakdown data is collected at various high voltages switching at 60 Hz over temperature. For reinforced insulation, VDE standard requires the use of TDDB projection line with failure rate of less than 1 part per million (ppm). Even though the expected minimum insulation lifetime is 20 years at the specified working isolation voltage, VDE reinforced certification requires additional safety margin of 20% for working voltage and 87.5% for lifetime which translates into minimum required insulation lifetime of 37.5 years at a working voltage that's 20% higher than the specified value.

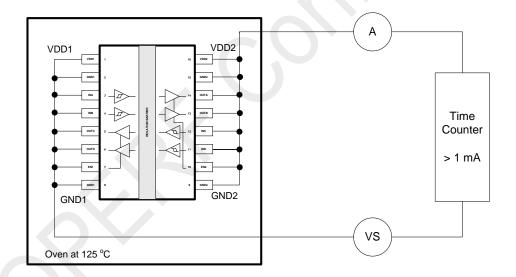


Figure 13. Test Setup for Insulation Lifetime Measurement

# 12 Packaging Information

The packaging information of the CMT826X SOIC16 is shown in the figures below.

### 12.1 CMT826X Narrow Body SOIC-16 Packaging

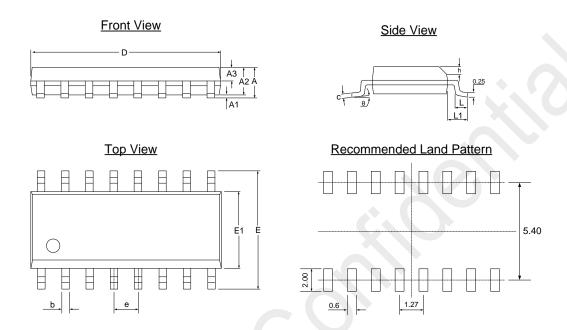


Figure 14. Narrow Body SOIC-16 Packaging

**Table 17.Narrow Body SOIC-16 Packaging Scale** 

0	Scale (mm)					
Symbol	Min.	Тур.	Max.			
Α	-	-	1.75			
A1	0.10	-	0.25			
b	0.36	-	0.49			
C	0.19	-	0.25			
D	9.80	9.90	10.0			
E	5.80	-	6.20			
E1	3.80	3.90	4.00			
е		1.27				
L	0.40	-	1.00			
L1		1.05				
θ	0	-	8°			

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## 12.2 CMT826X Wide Body SOIC-16 Packaging

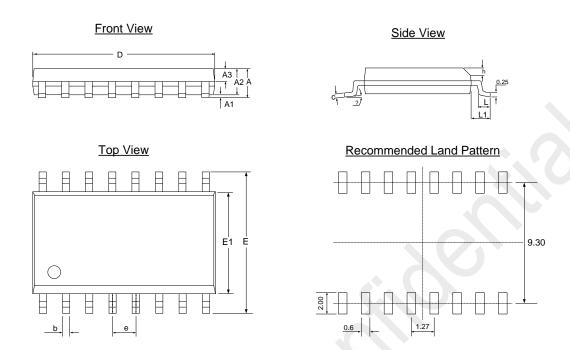


Figure 15. Wide Body SOIC-16 Packaging
Table 18. Wide Body SOIC-16 Packaging Scale

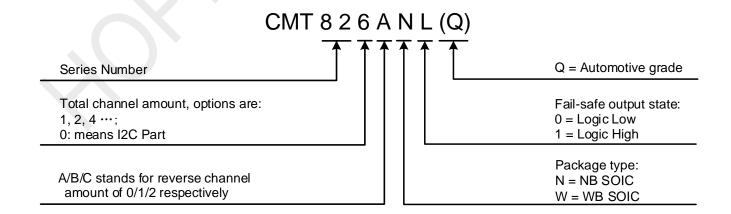
Complete I		Scale (mm)					
Symbol	Min.	Тур.	Max.				
А		-	2.65				
A1	0.10	0.20	0.30				
A2	2.25	2.30	2.35				
A3	1.00	1.05	1.10				
b	0.35	0.37	0.43				
С	0.15	0.20	0.30				
D	10.30	10.40	10.50				
E	10.10	10.30	10.50				
E1	7.40	7.50	7.60				
е	1.14	1.27	1.40				
L	0.65	0.70	0.85				
L1		1.40					
θ	0	-	8°				

# 13 Ordering Information

**Table 19. Part Number List** 

Part Number	MOQ	Isolatio n Voltage (kV)	Numbers of total channel	Nmubers of forward channels	Nmubers of reverse channels	Max Data Rate (Mbps)	Default Output Level	Automotiv e Grade	Package	MSL
CMT826AWL	1000	5	6	6	0	150	Low	No	WB SOIC-16	3
CMT826AWH	1000	5	6	6	0	150	High	No	WB SOIC-16	3
CMT826BWL	1000	5	6	5	1	150	Low	No	WB SOIC-16	3
CMT826BWH	1000	5	6	5	1	150	High	No	WB SOIC-16	3
CMT826CWL	1000	5	6	4	2	150	Low	No	WB SOIC-16	3
CMT826CWH	1000	5	6	4	2	150	High	No	WB SOIC-16	3
CMT826DWL	1000	5	6	3	3	150	Low	No	WB SOIC-16	3
CMT826DWH	1000	5	6	3	3	150	High	No	WB SOIC-16	3
CMT826ANL	3000	3.75	6	6	0	150	Low	No	NB SOIC-16	3
CMT826ANH	3000	3.75	6	6	0	150	High	No	NB SOIC-16	3
CMT826BNL	3000	3.75	6	5	1	150	Low	No	NB SOIC-16	3
CMT826BNH	3000	3.75	6	5	1	150	High	No	NB SOIC-16	3
CMT826CNL	3000	3.75	6	4	2	150	Low	No	NB SOIC-16	3
CMT826CNH	3000	3.75	6	4	2	150	High	No	NB SOIC-16	3
CMT826DNL	3000	3.75	6	3	3	150	Low	No	NB SOIC-16	3
CMT826DNH	3000	3.75	6	3	3	150	High	No	NB SOIC-16	3

### **Part Number Naming Rule:**



Please visit <a href="https://www.hoperf.com">www.hoperf.com</a> for more product/product line information.

Please contact <u>sales@hoperf.com</u> or your local sales representative for sales or pricing requirements.

## 14 Tape and Reel Information

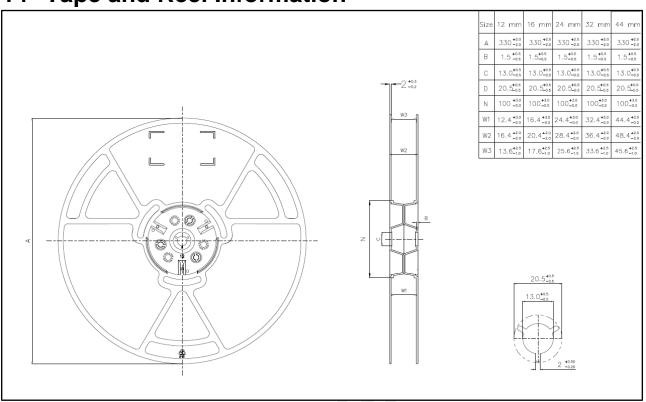
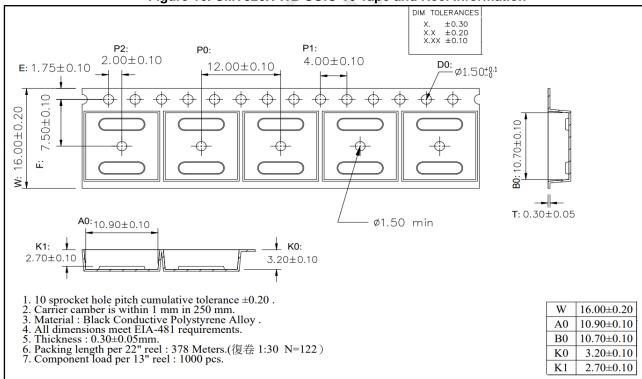


Figure 16. CMT826X WB SOIC-16 Tape and Reel Information



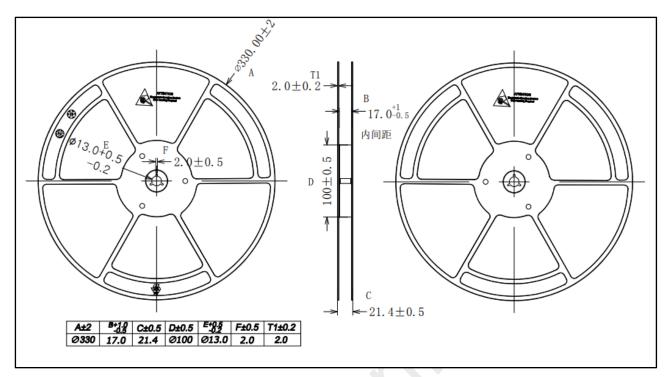


Figure 17. CMT826X WB SOIC-16 Tape and Reel Information

Figure 18. CMT826X NB SOIC-16 Tape and Reel Information

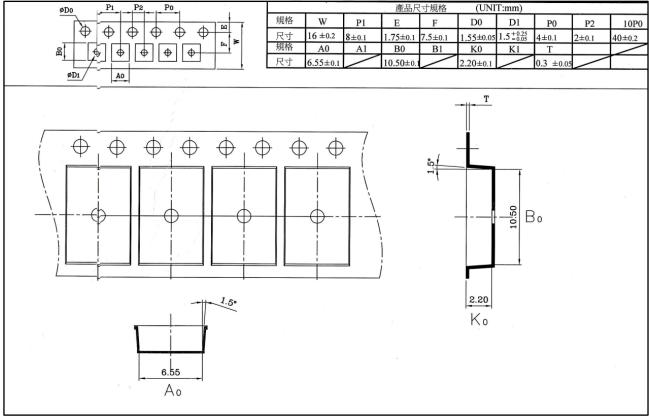


Figure 19. CMT826X NB SOIC-16 Tape and Reel Information

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# 15 Revise History

Table 20. Revise Records

Version No.	Chapter	Description	Date	
0.1	All	Initial version	2023/02/07	
0.2	13	Update silver print information	0000/0/00	
	15	Added tape information	2023/3/29	
0.3	All	Delete the silver printing section	2023/04/20	
		Added the CQC cercificate number		
0.4	All	Update the isolation voltage to 5.7 kVrms	2024/03/21	
		Add MSL in order information	2024/12/3	

### 16 Contacts

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